



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions

**11701 28th Street North
St. Petersburg, FL 33716**

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 December 2025

Certificate Number: AT-3054



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions

11701 28th Street North
St. Petersburg, FL 33716
Tony Giannetti 800 767 2637

TESTING

Valid to: **December 22, 2025**

Certificate Number: **AT-3054**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **A2 Global Electronics + Solutions** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Freedom Scientific HD MAG, Nikon, Vision, Amscope Microscopes.
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2		Mineral spirits, Isopropyl alcohol
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2		Calipers Auto Contactless Measurements
XRF	AS6081, 4.2.6.4.5 AS6171/3		Multiple X-ray Fluorescence Testing Equipment
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Multiple Radiological Testing Equipment
Scanning Electron Microscopy (SEM) Examination / Inspection	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C		Scanning Electron Microscope
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6		Scanning Acoustic Microscope (SAM)

Mechanical

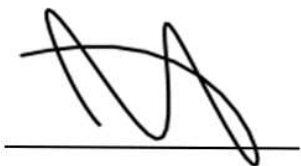
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Nisene JetEtch Pro, Paragon Oven.
Solderability	ANSI/J-STD-002		Solderability tester RPS 202TL-2 Reflow oven Madell Tech AE-R330
Wetting Balance Solder	ANSI/J-STD-002 MIL-STD-883		Wetting Balance Tester
Plating Thickness	AS6171/3		Plating Thickness Tester
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2		Hot plate, Acetone, 1-Methyl 2-Pyrrolidinone, Dynasolve 750 (or equivalent).

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Sect. C.3	Electrical, Electronic and Electromechanical (EEE) Components	ATE and various Electronic Lab Equipment
DC Test and Key Parameters AC, Switching, Functional Over Temperature	AS6171/7 MIL-STD-883		
DC Test and Key Parameters AC, Switching, Functional Ambient Temperature	AS6171/7 MIL-STD-883		

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3054.



Jason Stine, Vice President



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions (America II Asia Pte Ltd)

**151 Lorong Chuan
#06-05A, #06-06, #06-07
New Tech Park 556741
Republic of Singapore**

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
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Jason Stine, Vice President

Expiry Date: 22 December 2025

Certificate Number: AT-3054.01



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
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quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions (America II Asia Pte Ltd)

151 Lorong Chuan
#06-05A, #06-06, #06-07
New Tech Park 556741
Republic of Singapore
Tony Giannetti +1 800 767 2637 x 1043

TESTING

Valid to: **December 22, 2025**

Certificate Number: **AT-3054.01**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **A2 Global Electronics + Solutions** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Atto Instruments, Amscope Microscope, Dinolight
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2A		Mineral spirits, Isopropyl alcohol
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2A		Calipers, Contactless Measurement System
XRF	AS6081, 4.2.6.4.5 AS6171/3		Multiple X-ray fluorescence Testers
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Multiple Radiological Testers
Surface Texture Analysis	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C	Electrical, Electronic and Electromechanical (EEE) Components	Scanning Electron Microscope (SEM)
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6		Scanning Acoustic Microscope (SAM)

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Hot plate, Acetone, 1-Methyl 2-Pyrrolidinone, Dynasolve 750 or equivalent
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4		Decapsulation Furnace
Solderability	ANSI/J-STD-002		Solder Pot
Solder Wetting Balance Test	ANSI/J-STD-002 MIL-STD-883		Wetting Balance Tester
Coating / Plating Analysis	AS6171/3		X-ray fluorescence Plating Thickness Tester

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Sect. C.3	Electrical, Electronic and Electromechanical (EEE) Components	ATE and various Electronic Lab Equipment
Electrical, Key Parameters (AC, Switching, Functional) at ambient temp.	AS6171/7 MIL-STD-883		
Electrical, DC Test and Key Parameters (AC, Switching, Functional), over temp.	AS6171/7 MIL-STD-883		

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Jason Stine, Vice President



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

**A2 Global Electronics + Solutions
(America II Europe B.V.)**

**Rijnlanderweg 766, Unit C
2132NM Hoofddorp, The Netherlands**

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

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Jason Stine, Vice President

Expiry Date: 22 December 2025

Certificate Number: AT-3054.02



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

A2 Global Electronics + Solutions (America II Europe B.V.)

Rijnlanderweg 766, Unit C
2132NM Hoofddorp, The Netherlands
Tony Giannetti +1 800 767 2637 x1043

TESTING

Valid to: **December 22, 2025**

Certificate Number: **AT-3054.02**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **A2 Global Electronics + Solutions** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Multiple Microscopes
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2A		Mineral spirits, Isopropyl alcohol, Acetone
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2A		Digital Calipers, Auto Contactless Measurement
XRF	AS6081, 4.2.6.4.5 AS6171/3		Multiple X-ray Fluorescence Testing Equipment
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Multiple Radiological Testing Equipment

Non-Destructive Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6	Electrical, Electronic and Electromechanical (EEE) Components	Scanning Acoustic Microscope (SAM)

Mechanical


Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Furnace acid less oven
Solderability	ANSI/J-STD-002		Solder Pot Reflow Oven
Wetting Balance Solder	ANSI/J-STD-002 MIL-STD-883		Wetting Balance Tester
Plating Thickness	AS6171/3		Plating Thickness Tester
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2A		Hot Plate, Multiple Chemicals

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Section C.3	Electrical, Electronic and Electromechanical (EEE) Components	ATE and Various Electronic Lab Equipment
DC Test and Key Parameters (AC, Switching, Functional), Over Temperature	AS6171/7 MIL-STD-883		
DC Test and Key Parameters (AC, Switching, Functional), Ambient Temperature	AS6171/7 MIL-STD-883		

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Jason Stine, Vice President